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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
10/501,772	04/25/2005	Ulrich Bockelmann	255977US2PCT	8420	
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1940 DUKE STREET			CROW, ROBERT THOMAS		
ALEXANDRI	A, VA 22314		ART UNIT	PAPER NUMBER	
		1634			
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			05/27/2010	ELECTRONIC	

Please find below and/or attached an Office communication concerning this application or proceeding.

The time period for reply, if any, is set in the attached communication.

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Advisory Action Before the Filing of an Appeal Brief

Ī	Application No.	Applicant(s)	
	10/501,772	BOCKELMANN ET AL.	
	Examiner	Art Unit	
	Robert T. Crow	1634	

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The MAILING DATE of this communication appe	ars on the cover sheet with the o	orrespondence add	ress
THE REPLY FILED 07 May 2010 FAILS TO PLACE THIS APPI	LICATION IN CONDITION FOR AL	LOWANCE.	
 M The reply was filed after a final rejection, but prior to or on application, applicant must limely file one of the following application in condition for allowance; (2) a Notice of Appe for Continued Examination (RCE) in compliance with 37 C periods: 	replies: (1) an amendment, affidavi eal (with appeal fee) in compliance	t, or other evidence, w with 37 CFR 41.31; or	hich places the (3) a Request
a) The period for reply expires 5 months from the mailing date b) The period for reply expires on: (1) the mailing date of this Ax no event, however, will the statutory priorid for reply expire la Examiner Note: If box 1 is checked, check either box (a) or (I MONTHS OF THE FINAL REJECTION, See MPEP 706.)	dvisory Action, or (2) the date set forth inter than SIX MONTHS from the mailing b). ONLY CHECK BOX (b) WHEN THE	date of the final rejection	n.
Extensions of time may be obtained under 37 CFR 1.136(a). The date in have been filled is the date for purposes of eletermining the partie of under 37 CFR 1.17(a) is calculated from: (1) the expiration date of the set forth in (b) above, if checked, Any pely received by the Office later may reduce any earned patent term adjustment. See 37 CFR 1.704(b). NOTICE OF APPEAL	on which the petition under 37 CFR 1.1: ension and the corresponding amount of hortened statutory period for reply origithan three months after the mailing date	of the fee. The appropria nally set in the final Office	ate extension fee e action; or (2) as
The Notice of Appeal was filed on A brief in compl filling the Notice of Appeal (37 CFR 41.37(a)), or any exter Notice of Appeal has been filed, any reply must be filed with AMENDMENTS.	sion thereof (37 CFR 41.37(e)), to	avoid dismissal of the	
 The proposed amendment(s) filed after a final rejection, b (a) They raise new issues that would require further cor (b) They raise the issue of new matter (see NOTE below (c) They are not deemed to place the application in bett 	nsideration and/or search (see NOT w);	E below);	
appeal; and/or (d) They present additional claims without canceling a continuous NOTE: (See 37 CFR 1.116 and 41.33(a)).	corresponding number of finally reje	ected claims.	
The amendments are not in compliance with 37 CFR 1.12 Applicant's reply has overcome the following rejection(s): Newly proposed or amended claim(s) would be alled.			
non-allowable claim(s). To proproses of appeal, the proposed amendment(s): a) [how the new or amended claims would be rejected is prov The status of the claim(s) is (or will be) as follows: Claim(s) allowed: Claim(s) objected to: Claim(s) withdrawn from consideration:		be entered and an e	xplanation of
AFFIDAVIT OR OTHER EVIDENCE 8. The affidavit or other evidence filed after a final action, but because applicant failed to provide a showing of good and was not earlier presented. See 37 CFR 1.116(e).			
 The affidavit or other evidence filed after the date of filing entered because the affidavit or other evidence failed to or showing a good and sufficient reasons why it is necessary 	vercome <u>all</u> rejections under appea	l and/or appellant fail:	to provide a
 The affidavit or other evidence is entered. An explanation REQUEST FOR RECONSIDERATION/OTHER 	n of the status of the claims after er	ntry is below or attach	ed.
 The request for reconsideration has been considered but See Continuation Sheet. 	does NOT place the application in	condition for allowan	ce because:
12. Note the attached Information Disclosure Statement(s). (13. Other:	PTO/SB/08) Paper No(s).		
	/Robert T. Crow/	nit 1634	

Continuation of 11, does NOT place the application in condition for allowance because: Applicant's after-final arguments filed 7 May 2010 (hereafter the "Remarks") have been fully considered but they are not persuasive for the reasons discussed below.

A. Applicant argues on pages 3-4 that Lindsay et al allegedly teach a floating gate voltage, thereby making it impossible to fix both the potential or the fluid and the gate voltage so that it will be the same for all the FETs used. Thus, Applicant argues the teachings of Lindsay et al individually.

However, a review of Lindsay et al yields not teaching of a "floating" voltage. In addition, MPEP 716.01(c) makes clear that "(t)he arguments of counsel cannot take the place of evidence in the record" (nr e Schutz, 246 F.26 600, 602, 145 USPO 716, 718 (CCPA 1955)). Thus, counsel's mere arguments that Lindsay et at teach a floating gate voltage, thereby making it impossible to fix both the solential or the fluid and the cale voltage so that it will be the same for all the FETs used cannot take the bloce vidence in the record.

It is noted that the Response above should not be construed as an invitation to file an after final declaration. See MPEP 715.09 [R-3].

In response to applicant's arguments against the references individually, one cannot show nonobviousness by attacking references individually where the rejections are based on combinations of references. See In re Keller, 642 F.2d 413, 208 USPQ 871 (CCPA 1981); In re Merck & Co., 800 F.2d 1091, 231 USPQ 375 (Fed. Cir. 1986).

Further, Lindsay et all is not relied upon for the teaching fixing the potential of the active zones with an electrode that applies a gate source voltage to the FETs. Rather, Hafeman et all is relied upon for this teaching.

B. Applicant argues on page 5 of the Remarks that Kariyone et al does not teach simultaneous use of the electrodes, differential measurements, or transistors.

In response to applicant's argument that the references fail to show certain features of applicant's invention, it is noted that the features upon which applicant felles (i.e., simultaneous use of the electrodes) are not rested in the rejected claim(s). Although the claims are interpreted in light of the specification, limitations from the specification are not read into the claims. See In re Van Geuns, 988 F.2d 1181, 26 USPQ2d 1057 (Fed. Cir. 1993).

In addition, as noted in the previous Final Office Action, Kariyone et all is merely relied upon for the teaching of the known technique of measuring initial immobilization of a probe to a surface of a sensor. Lindsay et all teach differential measurements (paragraph 0032), which is only required by instant claim 8, and not by independent claim 1. Lindsay et all also teach the use of FET transistors (e.g., paragraph 0036).

D. Applicant argues on page 6 of the Remarks that the reference electrode of Kariyone et al cannot be readily included in the method of Lindsay et al.

However, it is reiterated that Kariyone et al is merely relied upon for the teaching of the known technique of measuring initial immobilization of a probe to a surface of a sensor, and therefore is not relied upon for a reference electrode. Thus, because Kariyone et al is not relied upon for a reference electrode. Applicant's arguments regarding "substantial reconstruction" for lindsay et al are moot.

Further, it is reiterated that the arguments of counsel cannot take the place of evidence in the record. Thus, counsel's mere arguments that Kariyone et al cannot be combined with Lindsay et al and that "substantial reconstruction" would be required cannot take the place of evidence in the record.

It is also reiterated that the Response above should not be construed as an invitation to file an after final declaration.

E. In response to Applicant's argument on pages 6-7 of the Remarks that Lindsay et all and Kariyone et all are nonanalogous art, it has been held that a prior art reference must either be in the field of applicant's endeavor or, if not, then be reasonably pertinent to the particular problem with which the applicant was concerned, in order to be relied upon as a basis for rejection of the claimed invention. See In re Oetiker, 977 F.2d 1443, 24 USPQ2d 1443 (Fed. Cir. 1992). In this case, both references relate to electrical detection of reactions of biological molecules.

Indeed, Applicant's own arguments on pages 6-7 of the Remarks confirm that the two references are analogous. Applicant oites paragraph 0010 of Lindsay et al, which discussed electrical detection of binding between two biomolecules (i.e., DNA hybridzation) via shifts in current. Applicant also argues Kariyone et al teach detection measurement current. Thus, the references are analogous.

F. Applicant argues on page 7 of the Remarks that the combination does not yield predictable results, and that "it is possible" that the combination is no longer operable.

However, Applicant provides no evidence to support this argument. Therefore, it is reiterated that the arguments of counsel cannot take the place of evidence in the record. Thus, counsel's mere arguments that the results are not predictable and the pure speculation that "it is possible" that the combination is no longer operable cannot take the place of evidence in the record.

It is also reiterated that the Response above should not be construed as an invitation to file an after final declaration.

Further, with respect to the predictability of the results, Kariyone et al clearly tech the electrical measurements made to detect the presence of the immobilization of the probe to the surface (column 17, lines 1-10). Thus, the known technique of using the initial detection of the immobilization of a probe taught by Kariyone et all predictably results in verification of stably immobilized probes.

G. Applicant argues on page 7 of the Remarks that Hafeman et al do not teach FETs.

However, as previously noted in the rejections, Hafeman et al is merely relied upon for using a fixed potential in a control electrode that sets the potential of the other electrodes, thereby providing the added advantage of allowing measurement of analyte binding (column 19, line 45-column 20, line 15) with maximal sensitivity (Abstract). Thus, Hafeman et al teach the known technique of fixing the potential of the active zones with a common electrode, which is analogous to the control FET electrode of Lindsay et al (i.e., not used for hybridization; paragraph 0040).

Therefore, as noted in the rejections, the application of the fixed potential in accordance with the teachings of Hafeman et al would result in the application of a gate source voltage to the field effect transistors of Lindsay et all in view of Kariyone et all, thus arriving at the instantly claimed method with a reasonable expectation of success

H. Applicant argues on pages 8-9 of the Remarks that the ordinary artisan would not use the electrodes of Hafeman et al in the method of Lindsay et al.

However, the rejection does not rely on this combination. As noted above, Hafeman et all is relied upon for the application of the fixed potential, which would result in the application of a gate source voltage to the field effect transistors of Lindsay et all in view of Kariyone et al. thus arriving at the instantive claimed method with a reasonable exceptation of success.

I. With respect to the comments of Hafeman et all that FET devices have not found commercial acceptance, it is noted that the patent of Hafeman et all was issued in 1992, whereas Lindsay et al, which does use FETs, was published in 2004, and clearly indicates the acceptance and desirability of FETs in nucleic acid assays. Thus, it would be obvious to the ordinarily skilled artisan that the later reference of Lindsay et all overrides the twelve year old comments of Hafeman et al.

Further, the main criticism of Hafeman et al concerns exposed gate regions (see page 8 of the Remarks). The FETs of Lindsay et al specifically allow the interaction of fluids in an experimental environment (paragraph 0019 of Lindsay et al), thus negating the criticism offered by Hafeman et al.

/Robert T. Crow/ Primary Examiner, Art Unit 1634